

August 2014

# FQP15P12 / FQPF15P12 P-Channel QFET® MOSFET

-120 V, -15 A, 0.2  $\Omega$ 

## **Description**

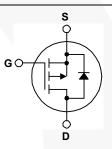
This P-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor<sup>®</sup>'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, audio amplifier, DC motor control, and variable switching power applications.

## **Features**

- -15 A, -120 V,  $R_{DS(on)}$  = 0.2  $\Omega$  (Max.) @  $V_{GS}$ =-10 V,  $I_D$  = -7.5 A
- Low Gate Charge (Typ. 29 nC)
- Low Crss (Typ. 110 pF)
- 100% Avalanche Tested
- · 175°C Maximum Junction Temperature Rating







# Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted.

Symbol	Parameter		FQP15P12	FQPF15P12	Unit
V <sub>DSS</sub>	Drain-Source Voltage		-120		V
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C)		-15	-15 *	Α
	- Continuous (T <sub>C</sub> = 100°	C)	-10.6	-10.6 *	Α
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	-60	-60 *	Α
$V_{GSS}$	Gate-Source Voltage		± 30		V
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2		1157		mJ
I <sub>AR</sub>	Avalanche Current	(Note 1)	-15		Α
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	10		mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		-5.0		V/ns
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> = 25°C)		100	41	W
	- Derate above 25°C		0.67	0.27	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +175		°C
T <sub>L</sub>	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds		300		°C

<sup>\*</sup> Drain current limited by maximum junction temperature.

## **Thermal Characteristics**

Symbol	Parameter	FQP15P12	FQPF15P12	Unit
$R_{ heta JC}$	Thermal Resistance, Junction-to-Case	1.5	3.66	°C/W
$R_{\theta JS}$	Thermal Resistance, Case-to-Sink Typ.	40		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	62.5	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Off Cha	racteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA	-120			V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D$ = -250 μA, Referenced to 25°C		-0.13		V/°C
I <sub>DSS</sub>	Zoro Cato Voltago Drain Current	V <sub>DS</sub> = -120 V, V <sub>GS</sub> = 0 V		-	-1	μΑ
	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -96 V, T <sub>C</sub> = 150°C			-10	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V		-	-100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V		ı	100	nA
On Cha	racteristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-2.0		-4.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = -10 V, I <sub>D</sub> = -7.5 A		0.17	0.2	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = -40 V, I <sub>D</sub> = -7.5 A		9.5		S
<b>Dynam</b> i C <sub>iss</sub>	ic Characteristics Input Capacitance	V <sub>DS</sub> = -25 V, V <sub>GS</sub> = 0 V,		850	1100	pF
C <sub>oss</sub>	Output Capacitance	f = 1.0  MHz	\	310	400	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1.0 (VII 12		110	140	pF
	ng Characteristics					
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = -60 V, I <sub>D</sub> = -15 A,		15	40	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$		100	210	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	01-1- 0		80	170	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4)		80	170	ns
$Q_g$	Total Gate Charge	$V_{DS} = -96 \text{ V}, I_{D} = -15 \text{ A},$		29	38	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = -10 V		5.1		nC
$Q_{gd}$	Gate-Drain Charge	(Note 4)		15		nC
Drain-S	ource Diode Characteristics a	nd Maximum Ratings				
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current				-15	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current				-60	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = -15 A			-4.0	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = -15 A,		126	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	dI <sub>F</sub> / dt = 100 A/μs		0.61		μC

Notes: 1. Repetitive rating : pulse width limited by maximum junction temperature. 2. L = 6.0mH, I $_{AS}$  = -15A, V $_{DD}$  = -50V, R $_{G}$  = 25  $\Omega$ , starting T $_{J}$  = 25°C. 3. I $_{SD}$  ≤ -15A, di/dt ≤ 300A/ $\mu$ s, V $_{DD}$  ≤ BV $_{DSS}$ , starting T $_{J}$  = 25°C. 4. Essentially independent of operating temperature.

# **Typical Characteristics**

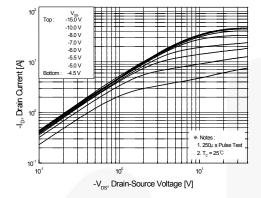


Figure 1. On-Region Characteristics

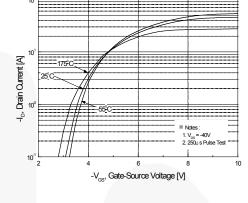


Figure 2. Transfer Characteristics

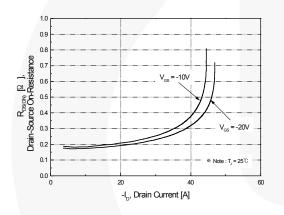


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

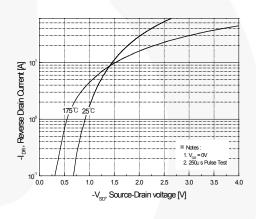


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

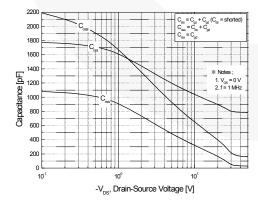


Figure 5. Capacitance Characteristics

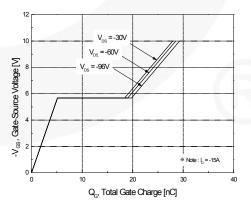


Figure 6. Gate Charge Characteristics

# Typical Characteristics (Continued)

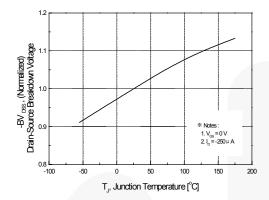


Figure 7. Breakdown Voltage Variation vs Temperature

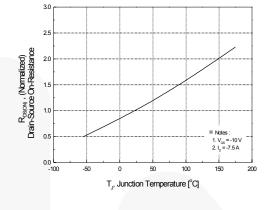


Figure 8. On-Resistance Variation vs Temperature

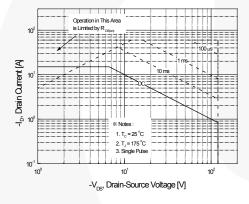


Figure 9-1. Maximum Safe Operating Area for FQP15P12

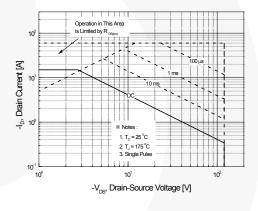


Figure 9-2. Maximum Safe Operating Area for FQPF15P12

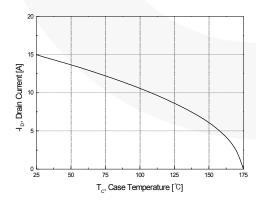


Figure 10. Maximum Drain Current vs Case Temperature

# **Typical Characteristics** (Continued)

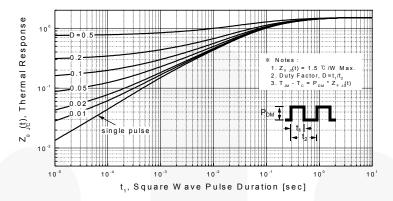


Figure 11-1. Transient Thermal Response Curve for FQP15P12

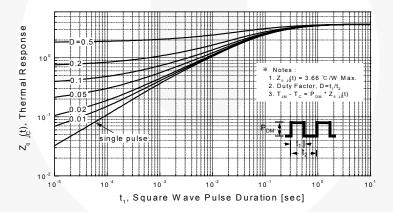


Figure 11-2. Transient Thermal Response Curve for FQPF15P12

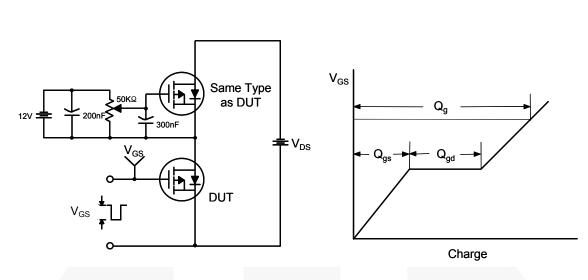


Figure 12. Gate Charge Test Circuit & Waveform

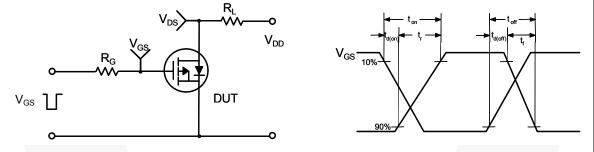


Figure 13. Resistive Switching Test Circuit & Waveforms

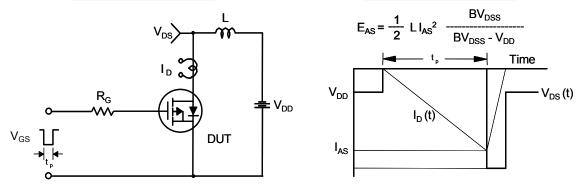
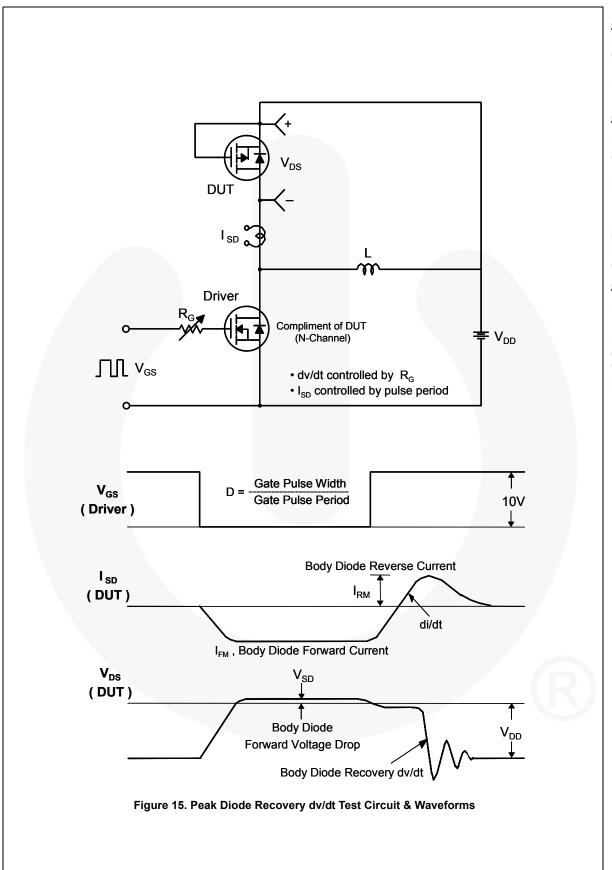
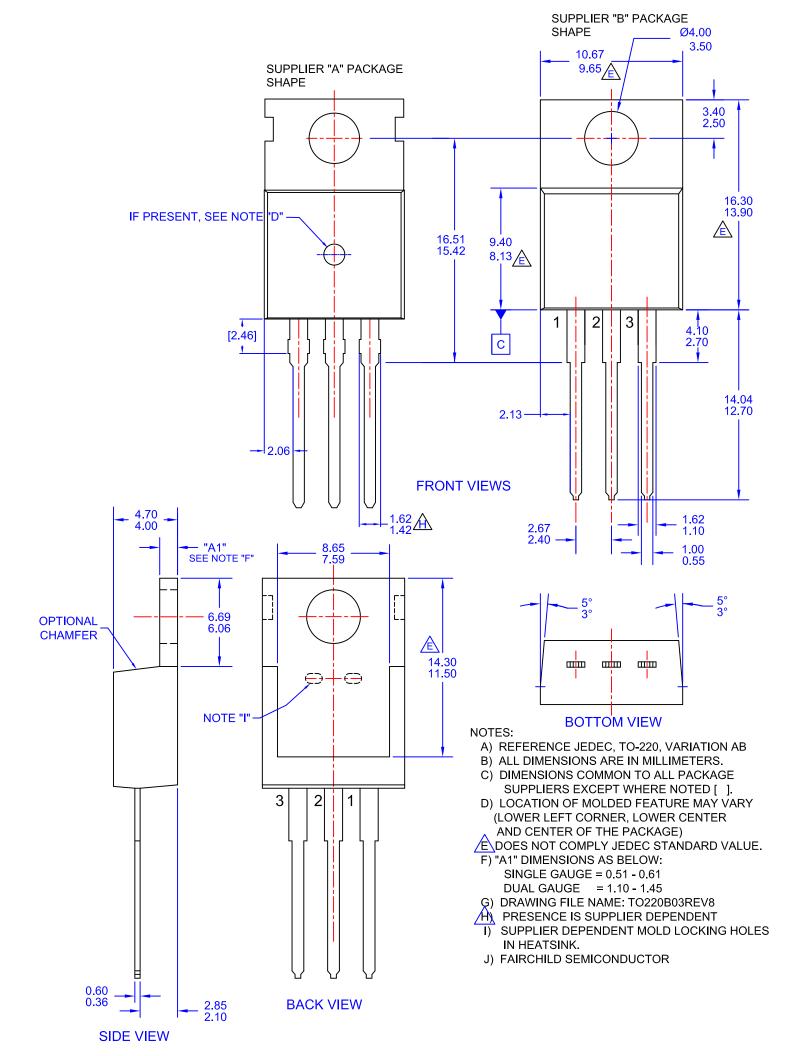
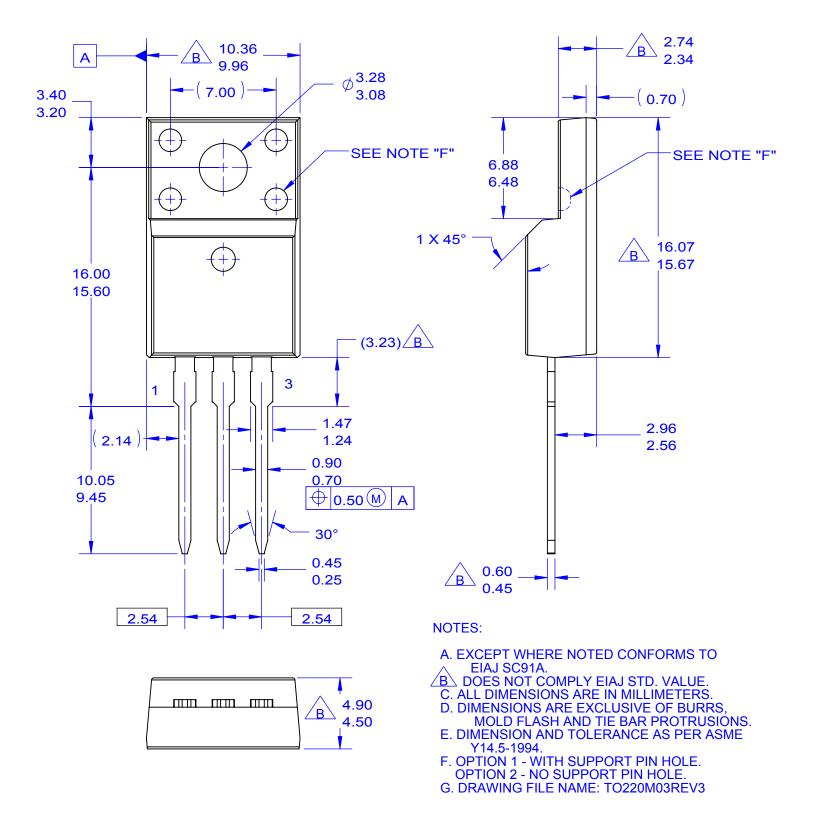


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms











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